Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	r
10/519,831	KOHINATA ET AL.	
Examiner	Art Unit	
Ellen Kim	2874	

SEARCHED				
Class	Subclass	Date	Examiner	
385	11	8/13/2006	EK	
528	34	8/13/2006	EK	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
385	11	8/13/2006	EK	
528	34	8/13/2006	EK	
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SEARCH (INCLUDING SEAR	NOTES CH STRATEGY)
	DATE	EXMR
East	8/13/2006	EK
STN [done by EIC]	8/4/2006	EK